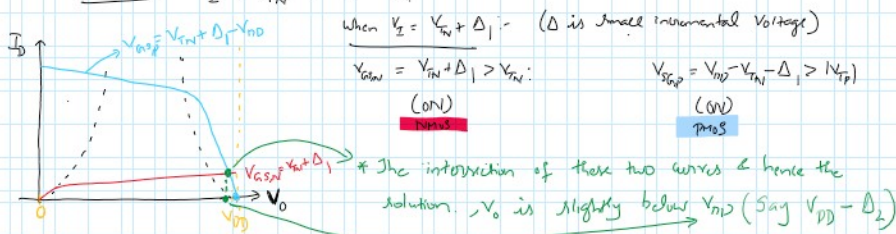


Case IV: $V_I > V_{TN}$ & $V_I < V_M$ 

* From the I-V curve, NMOS is in saturation & PMOS is in linear region.

NMOS

$$V_{DS} \geq V_{GS} - V_{TN} \text{ for saturation.}$$

$$V_O \geq V_I - V_{TN}$$

$$V_{DD} - \Delta_2 \geq V_{TN} + \Delta_1 - V_{TN}$$

$$V_{DD} \geq \Delta_1 + \Delta_2 \quad (\text{true})$$

 \therefore NMOS is in saturationPMOS

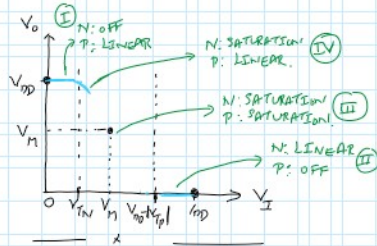
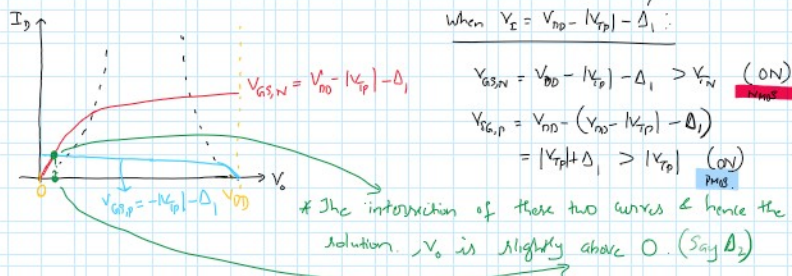
$$V_{SD} \geq |V_{GS} - V_{TP}| \text{ for saturation}$$

$$V_{DD} - V_O \geq |V_{DD} - V_I - V_{TP}|$$

$$V_O \leq V_I + |V_{TP}|$$

$$V_{DD} - \Delta_2 \leq V_{TN} + \Delta_1 + |V_{TP}|$$

$$V_{DD} \leq \Delta_1 + \Delta_2 + |V_{TP}| + V_{TN} \quad (\text{False})$$

 \therefore PMOS is in linear region.Case V: $V_I < V_{DD} - |V_{TP}| - \Delta_1$ & $V_I > V_M$ 

* From the I-V curve, NMOS is in linear & PMOS is in saturation region.

NMOS

$$V_{DS} \geq V_{GS} - V_{TN} \text{ for saturation.}$$

$$V_O \geq V_I - V_{TN}$$

$$\Delta_2 \geq V_{DD} - |V_{TP}| - \Delta_1 - V_{TN}$$

$$\Delta_2 \geq V_{DD} - (V_{TN} + |V_{TP}|) - \Delta_1 \quad (\text{FALSE})$$

 \therefore NMOS is in linear region.PMOS

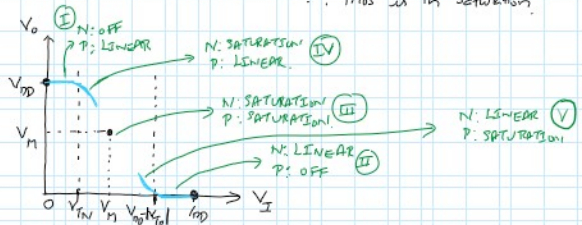
$$V_{SD} \geq |V_{GS} - V_{TP}| \text{ for saturation}$$

$$V_{DD} - V_O \geq |V_{DD} - V_I - V_{TP}|$$

$$V_O \leq V_I + |V_{TP}|$$

$$\Delta_2 \leq V_{DD} - |V_{TP}| - \Delta_1 + |V_{TP}|$$

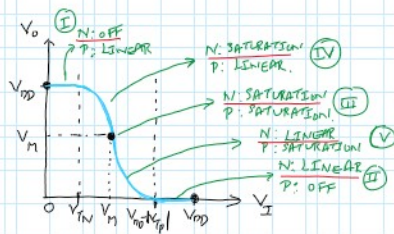
$$\Delta_2 \leq V_{DD} - \Delta_1 \quad (\text{true})$$

 \therefore PMOS is in saturation.

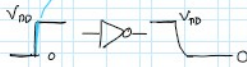
* Final transfer curve of an inverter is:-



* Final transfer curve of an inverter is:-



* As V_I changes from 0 to V_{DD} } NMOS transitions from OFF \rightarrow SATURATION \rightarrow LINEAR
 PMOS transitions from LINEAR \rightarrow SATURATION \rightarrow OFF



* Let's try to evaluate V_M (i.e. the voltage @ which $V_I = V_O$)

* Recall that in case III ($V_I = V_O = V_M$), both NMOS & PMOS are in saturation.

$$I_{D,NMOS,sat} = I_{D,PMOS,sat} \quad (\text{ignoring channel length modulation})$$

$$\frac{1}{2} \mu_n \left(\frac{W}{L} \right)_N (V_{GS} - V_{TN})^2 = \frac{1}{2} \mu_p \left(\frac{W}{L} \right)_P (V_{GS} - |V_{TP}|)^2$$

$$\underbrace{\mu_n \left(\frac{W}{L} \right)_N}_{K_N} (V_M - V_{TN})^2 = \underbrace{\mu_p \left(\frac{W}{L} \right)_P}_{K_P} (V_{DD} - V_M - |V_{TP}|)^2$$

$$\therefore K_N [V_M - V_{TN}]^2 = K_P [V_{DD} - V_M - |V_{TP}|]^2$$

$$V_M - V_{TN} = \sqrt{\frac{K_P}{K_N}} [V_{DD} - V_M - |V_{TP}|]$$

$$\text{Define } \beta = \sqrt{\frac{K_P}{K_N}} \quad V_M - V_{TN} = \beta [V_{DD} - V_M - |V_{TP}|]$$

$$V_M [1 + \beta] = \beta [V_{DD} - |V_{TP}|] + V_{TN}$$

$$\therefore V_M = \frac{V_{TN} + \beta [V_{DD} - |V_{TP}|]}{1 + \beta}$$

* V_M (also called "Switching Voltage" or "Trip-point Voltage" of an inverter) is a function of

$$V_{TN}, |V_{TP}|, \mu_n, \mu_p, \left(\frac{W}{L} \right)_N \text{ \& } \left(\frac{W}{L} \right)_P.$$

* The only design parameter (available for designer) is $\left(\frac{W}{L} \right)_N$ & $\left(\frac{W}{L} \right)_P$.

* Consider the special case where $V_{TN} = |V_{TP}|$ and $\beta = 1$

$$V_M = \frac{V_{TN} + V_{DD} - V_{TN}}{2} = V_{DD}/2$$

i.e. for a exactly symmetric inverter (switching voltage $V_M = V_{DD}/2$) $\beta = 1$ AND $V_{TN} = |V_{TP}|$.

$$\beta = 1 \Rightarrow K_N = K_P \Rightarrow \mu_n \left(\frac{W}{L} \right)_N = \mu_p \left(\frac{W}{L} \right)_P$$

$$\frac{\left(\frac{W}{L} \right)_P}{\left(\frac{W}{L} \right)_N} = \frac{\mu_n}{\mu_p}$$

* For same PMOS & NMOS channel length [usually L_{min}],

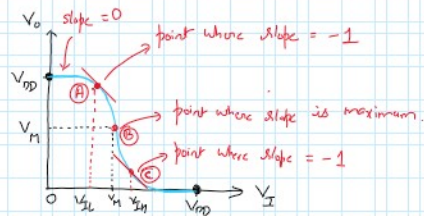
$$\frac{W_p}{W_n} = \frac{\mu_n}{\mu_p}$$

i.e. the ratio of PMOS to NMOS width = ratio of electron to hole mobilities.

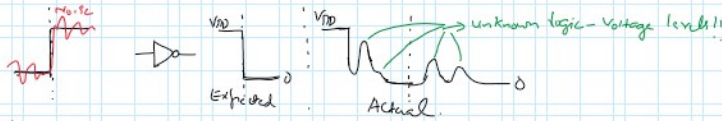
* Typically $\mu_n = f \cdot \mu_p$ & $f = 2$ or 2.5 or 3 .

* Note that if $V_{TN} \neq |V_{TP}|$ (which is usually the case), $W_p/W_n \neq \mu_n/\mu_p$ for $V_M = V_{DD}/2$

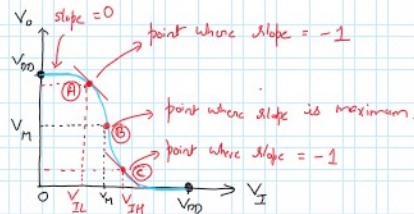
* Let's go back to the transfer curve of the inverter.



* The inverter's function is to operate as a digital switching logic without amplifying noise. Amplifying noise can change the logic level at the output.

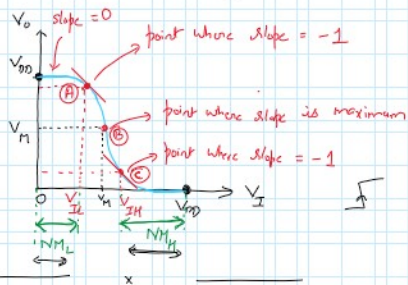


- * For faithful operation, we need to define noise margins of the inverter (V_{OH} & V_{IL} inputs)
- * Before Point (A) on the transfer curve, the magnitude of the slope is either 0 or < 1
 \Rightarrow No amplification happens (\because slope corresponds to gain)
- * After Point (C) on the transfer curve, the magnitude of the slope is either 0 or < 1
 \Rightarrow No amplification happens (\because slope corresponds to gain)

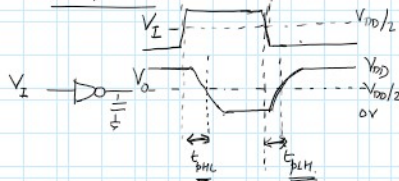


- * V_I below V_{IL} are not amplified, V_I above V_{IH} are not amplified.
- * In region (B) the inverter is acting as an amplifier with maximum gain.
 [Both PMOS & NMOS in the saturation Region] \rightarrow FOI analog designers.
- * We define Noise margin High (NM_H) & Noise Margin Low (NM_L)

$$NM_H = V_{DD} - V_{IH} \quad \& \quad NM_L = V_{IL}$$

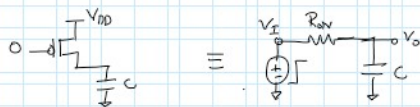


Transient characteristics of the inverter:-



- * Let's define propagation delay as the time taken for the output to reach 50% of the maximum input
- $\hookrightarrow t_{PHL} \rightarrow$ propagation delay when o/p goes from high to low
- $t_{PLH} \rightarrow$ propagation delay when o/p goes from low to high.

* When $V_I = 0$, PMOS is ON & the equivalent circuit is



$$V_O = V_I (1 - e^{-t/R_OV C})$$

For $t = t_{p, LH}$, $0.5V_I = V_I (1 - e^{-t_{p, LH}/R_OV C})$

$$\Rightarrow t_{p, LH} = 0.69 R_{OVP} C$$

* Recall that the PMOS goes OFF \rightarrow SATURATION \rightarrow LINEAR region. Assuming the time spent in saturation region is very small (for first-hand propagation calculations),

$$R_{OVP} = \frac{1}{\mu_p C_{ox} \left(\frac{W}{L}\right)_p (V_{DD} - |V_{TP}|)}$$

* Similarly for NMOS; $t_{p, HL} = 0.69 R_{OVP} C$

$$R_{OVP} = \frac{1}{\mu_n C_{ox} \left(\frac{W}{L}\right)_n (V_{DD} - V_{TN})}$$

* For Symmetric Inverter, $t_{p, LH} = t_{p, HL}$

$$\therefore 0.69 R_{OVP} \neq 0.69 R_{OVP} \neq$$

$$\Rightarrow \underbrace{\mu_p C_{ox} \left(\frac{W}{L}\right)_p}_{K_p} [V_{DD} - |V_{TP}|] = \underbrace{\mu_n C_{ox} \left(\frac{W}{L}\right)_n}_{K_n} [V_{DD} - V_{TN}]$$

$$\left(\frac{K_p}{K_n}\right) [V_{DD} - |V_{TP}|] = V_{DD} - V_{TN}$$

$$\delta^2 [V_{DD} - |V_{TP}|] = V_{DD} - V_{TN} \quad \text{--- (1)}$$

* Condition (1) above is true provided $V_{TN} = |V_{TP}|$ & $\delta = 1$

This is the same condition we got for $V_M = V_{DD}/2$!!!

* We define rise-time (t_r) & fall-time (t_f) as 20% to 80% V_{DD} time & vice versa.



* Under the same concept, if $t_{p, LH}$ & $t_{p, HL}$ are symmetric t_f & t_r will also be symmetric !!

\therefore Provided $V_{TN} = |V_{TP}|$, if by design $\delta = 1$ (i.e. $\frac{W_p}{W_n} = \frac{\mu_n}{\mu_p}$), we get

$$\left. \begin{array}{l} \text{(i) } V_M = V_{DD}/2 \\ \text{(ii) } t_{p, HL} = t_{p, LH} \\ \text{(iii) } t_r = t_f \end{array} \right\} \text{Symmetric Inverter}$$

* For an Inverter, we can define the following

(a) Static characteristics:

(i) V_M (Switching Voltage)

(ii) $V_{IH}, V_{OH} \in \underline{N_{MH}, N_{ML}}$ (Noise Margins)

(b) Dynamic characteristics:

(i) $t_{p, LH}$ & $t_{p, HL}$ (Low to High & High-to-low propagation time)

(ii) $t_p = \frac{t_{p, LH} + t_{p, HL}}{2}$ (total propagation time)

$$v_{PLH} = v_{PMH} \dots \dots \dots 0 \dots \dots \dots 0$$

$$(ii) t_p = \frac{t_{p, LH} + t_{p, HL}}{2} \text{ (total propagation time)}$$

$$(iii) t_r \& t_f \text{ (Rise \& fall time)}$$

* To design a symmetric inverter, i.e. $\begin{bmatrix} V_{th} = V_{th/2} \\ t_{p, LH} = t_{p, HL} \\ t_r = t_f \end{bmatrix}$,

if $V_{th} = |V_{th}|$, for a given minimum length (L_{min}), $\frac{W_p}{W_n} = \frac{\mu_n}{\mu_p}$.

→ This will be the starting point for your simulations.

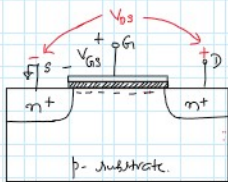
→ In a practical Process Design Kit (PDK), $V_{th} \neq |V_{th}|$

⇒ To achieve symmetric conditions W_p, W_n must be tuned.

— x — x —

Capacitance of MOSFET:

a) Due to channel:-



* When the MOSFET is ON (linear or saturation), there exists a capacitance between gate & source (C_{gs})

i.e top-plate of cap → Gate Metal
dielectric → gate oxide

& bottom-plate of cap → Channel connected to source

* When the MOSFET is in linear region, there also exists a capacitance b/w Gate & Drain (C_{gd})

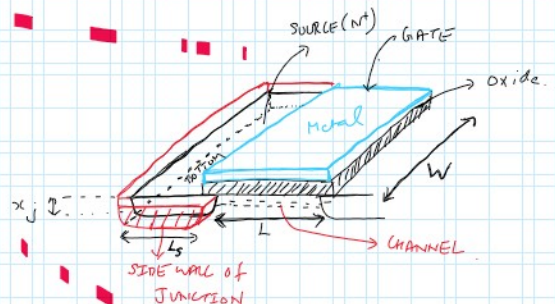
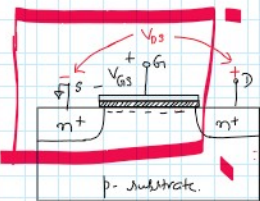
(Remember, in saturation, the channel does not extend to the drain because of depletion, hence no capacitance b/w gate & drain)

∴ Effectively:-



when MOS is in linear region.

b) Due to junctions (P-N):-



* There is a P-N junction on the bottom side of the source (and corresponding top surface of substrate)

* There is a P-N junction on the bottom side of the source (and corresponding top surface of substrate)

If C_j is the junction cap/unit-area, $C_{\text{bottom}} = C_j \times W \times L_s$

* There are P-N junctions on three sides of the source (except for the fourth side towards the gate)

The depth x_j is fixed for a given process. If C_{sw} is the side-wall cap/unit area,

If C_{jsw} is the side-wall capacitance,

$$C_{jsw} = C_{sw} \times \left[\underbrace{(x_j \times L_s)}_{\text{sidewall 1 area}} + \underbrace{(x_j \times L_s)}_{\text{sidewall 2 area}} + \underbrace{(x_j \times W)}_{\text{sidewall 3 area}} \right]$$

$$= C_{sw} x_j [2L_s + W]$$

$$\therefore C_{jsw} = \underbrace{C_{jsw}}_{\text{depends on the technology}} [2L_s + W]$$

∴ Capacitance due to junctions, also called diffusion capacitance is

$$C_{\text{diff}} = C_{\text{bottom}} + C_{jsw}$$

$$= C_j \times \text{AREA} + C_{jsw} \times \text{PERIMETER}$$

$$C_{\text{diff}} = C_j L_s W + C_{jsw} [2L_s + W]$$

* Look out for "as, ad, fs, fd" spice parameters in your assignment-1.

— x — x — x —